

REVISIONS

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
D	Add device type 02. Add CAGE 04713 as supplier. Editorial changes throughout.	93-08-20	Monica L. Poelking
E	Changes in accordance with NOR 5962-R013-94.	93-10-21	Monica L. Poelking
F	Add device type 03. Add CAGE 27014 as supplier. Editorial changes throughout.	94-01-05	Monica L. Poelking
G	Update boilerplate to MIL-PRF-38535 requirements. Editorial changes throughout. - LTG	03-07-09	Thomas M. Hess
H	Made change to paragraph 3.5. Update boilerplate to MIL-PRF-38535 requirements. - LTG	05-01-26	Thomas M. Hess
J	Update boilerplate paragraphs to the current MIL-PRF-38535 requirements. - LTG	11-07-26	Thomas M. Hess

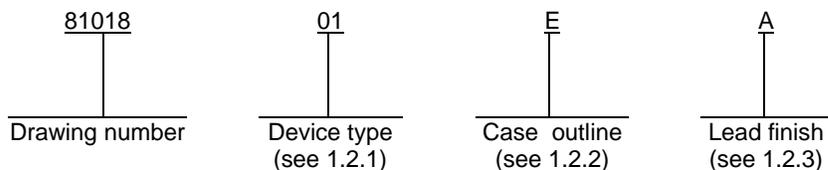
CURRENT CAGE CODE 67268

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REV STATUS	REV	J	J	J	J	J	J	J	J	J	J	J	J	J	J	J	J	J	J	J
OF SHEETS	SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13						
PMIC N/A	PREPARED BY Marcia B. Kelleher	<p align="center">DLA LAND AND MARITIME COLUMBUS, OHIO 43218-3990 http://www.dsc.dla.mil</p> <p>MICROCIRCUIT, DIGITAL, CMOS, TRIPLE 2-CHANNEL ANALOG MULTIPLEXER/ DEMULPLEXER, MONOLITHIC SILICON</p>																		
<p align="center">STANDARD MICROCIRCUIT DRAWING</p> <p>THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE</p> <p align="center">AMSC N/A</p>	CHECKED BY Monica L. Poelking																			
	APPROVED BY Michael A. Frye																			
	DRAWING APPROVAL DATE 82-02-04																			
	REVISION LEVEL J																			
	SIZE A	CAGE CODE 14933	81018																	
	SHEET		1 OF 13																	

1. SCOPE

1.1 Scope. This drawing describes device requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A.

1.2 Part or Identifying Number (PIN). The complete PIN is as shown in the following example:



1.2.1 Device type(s). The device type(s) identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	4053B	Triple 2-channel analog multiplexer/demultiplexer
02	14053B	Triple 2-channel analog multiplexer/demultiplexer
03	4053B	Triple 2-channel analog multiplexer/demultiplexer

1.2.2 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
E	GDIP1-T16 or CDIP2-T16	16	Dual-in-line
F	GDFP2-F16 or CDFP3-F16	16	Flat pack

1.2.3 Lead finish. The lead finish is as specified in MIL-PRF-38535, appendix A.

1.3 Absolute maximum ratings. 1/ 2/ 3/

Supply voltage range (V_{DD}):	
Device type 01	-0.5 V dc to +20 V dc
Device types 02 and 03	-0.5 V dc to +18 V dc
Input voltage range	-0.5 V dc to $V_{DD} + 0.5$ V dc
DC input current	± 10 mA
Storage temperature range	-65°C to +150°C
Maximum power dissipation (P_D):	
Device types 01 and 03	500 mW <u>4/</u>
Device type 02	300 mW <u>4/</u>
Lead temperature (soldering, 10 seconds):	
Device types 01 and 02	+300°C
Device type 03	+260°C
Thermal resistance, junction-to-case (θ_{JC})	See MIL-STD-1835
Junction temperature (T_J)	+175°C

- 1/ Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.
- 2/ Voltages referenced to V_{SS} or V_{EE} , whichever is more negative.
- 3/ The limits for the parameters specified herein shall apply over the full specified V_{CC} range and case temperature range of -55°C to +125°C.
- 4/ For $T_C = +100^\circ\text{C}$ to +125°C, derate linearly at 12 mW/°C to 200 mW.

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1.4 Recommended operating conditions.

Supply voltage range (V_{DD}):

Device type 01 +3.0 V dc to +18 V dc

Device types 02 and 03 +3.0 V dc to +15 V dc

Case operating temperature range (T_C) -55°C to +125°C

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.

MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.

MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at <https://assist.daps.dla.mil/quicksearch/> or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-PRF-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-PRF-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-PRF-38535 is required to identify when the QML flow option is used.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535, appendix A and herein.

3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.2 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.3 Truth table. The truth table shall be as specified on figure 2.

3.2.4 Logic diagram. The logic diagram shall be as specified on figure 3.

3.2.5 Switching waveforms and test circuit. The switching waveforms and test circuit shall be as specified on figure 4.

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3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full case operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-PRF-38535, appendix A. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-HDBK-103 (see 6.6 herein).

3.5.1 Certification/compliance mark. A compliance indicator "C" shall be marked on all non-JAN devices built in compliance to MIL-PRF-38535, appendix A. The compliance indicator "C" shall be replaced with a "Q" or "QML" certification mark in accordance with MIL-PRF-38535 to identify when the QML flow option is used.

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6 herein). The certificate of compliance submitted to DLA Land and Maritime -VA prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38535, appendix A and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DLA Land and Maritime -VA shall be required for any change that affects this drawing.

3.9 Verification and review. DLA Land and Maritime, DLA Land and Maritime's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Test conditions -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Quiescent supply current	I _{DD}	V _{DD} = 5 V <u>1/</u> V _{IN} = 0.0 V or V _{DD}	1, 3	All		5.0	μA
			2			150	
		V _{DD} = 10 V <u>1/</u> V _{IN} = 0.0 V or V _{DD}	1, 3	All		10.0	
			2			300	
		V _{DD} = 15 V <u>1/</u> V _{IN} = 0.0 V or V _{DD}	1, 3	All		20.0	
			2			600	
		V _{DD} = 20 V <u>2/</u> V _{IN} = 0.0 V or V _{DD}	1, 3	01		100	
			2			3000	
Low level input voltage	V _{IL}	V _{DD} = 5 V V _{EE} = V _{SS} R _L = 1 kΩ to V _{SS} I _{OL} = +2 μA V _O = 0.5 V or 4.5 V	1, 2, 3	All		1.5	V
		V _{DD} = 10 V, V _{EE} = V _{SS} R _L = 1 kΩ to V _{SS} <u>1/</u> I _{OL} = +2 μA V _O = 1.0 V or 9.0 V	1, 2, 3	All		3.0	
		V _{DD} = 15 V, V _{EE} = V _{SS} R _L = 1 kΩ to V _{SS} I _{OL} = +2 μA V _O = 1.5 V or 13.5 V	1, 2, 3	All		4.0	
High level input voltage	V _{IH}	V _{DD} = 5 V, V _{EE} = V _{SS} R _L = 1 kΩ to V _{SS} I _{OH} = -2 μA V _O = 0.5 V or 4.5 V	1, 2, 3	All	3.5		V
		V _{DD} = 10 V, V _{EE} = V _{SS} R _L = 1 kΩ to V _{SS} <u>1/</u> I _{OH} = -2 μA V _O = 1.0 V or 9.0 V	1, 2, 3	All	7.0		
		V _{DD} = 15 V, V _{EE} = V _{SS} R _L = 1 kΩ to V _{SS} I _{OH} = -2 μA V _O = 1.5 V or 13.5 V	1, 2, 3	All	11.0		
Input current	I _{IN}	V _{DD} = 15 V V _{IN} = 0.0 V or V _{DD}	1, 3	02, 03		±0.1	μA
			2			±1.0	
		V _{DD} = 20 V V _{IN} = 0.0 V or V _{DD} <u>2/</u>	1, 3	01		±0.1	
			2			±1.0	
Input capacitance	C _{IN}	V _{IN} = 0.0 V T _C = +25°C See 4.3.1c	4	01, 02		7.5	pF
			Control inputs A, B, C	4	03		
		Signal (IN/OUT) inputs ax, bx, ay, by, cy, cx				15	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Test conditions -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit	
					Min	Max		
OFF channel leakage current (all channels off)	I _{OFF1}	V _{DD} = 18 V V _{EE} = 0.0 V	1, 3	01	-100	+100	nA	
			2		-1000	+1000		
		V _{DD} = 15 V V _{EE} = 0.0 V	1, 3	02	-100	+100		
			2		-1000	+1000		
		V _{DD} = 15 V V _{EE} = 0.0 V	1, 3	03	-200	+200		
			2		-2000	+2000		
OFF channel leakage current (any channels off)	I _{OFF2}	V _{DD} = 18 V V _{EE} = 0.0 V	1, 3	01	-100	+100		
			2		-1000	+1000		
		V _{DD} = 15 V V _{EE} = 0.0 V	1, 3	02	-100	+100		
			2		-1000	+1000		
		V _{DD} = 15 V V _{EE} = 0.0 V	1, 3	03	-50	+50		
			2		-500	+500		
On-state resistance	R _{ON}	V _{DD} = 5.0 V V _{EE} = 0.0 V V _{SS} = 0.0 V	1	01, 02		1050	Ω	
			2			1300		
			3			800		
			1	03		2500		
			2			3500		
			3			2000		
			V _{DD} = 10 V V _{EE} = 0.0 V V _{SS} = 0.0 V	1	01			400
				2				550
				3				310
				1	02			500
				2				550
				3				400
		V _{DD} = 10 V V _{EE} = 0.0 V V _{SS} = 0.0 V	1	03		400		
			2			580		
			3			310		
			V _{DD} = 15 V V _{EE} = 0.0 V V _{SS} = 0.0 V	1	01			240
				2				320
				3				200
		1		02		280		
		2				320		
		3				220		
		1		03		280		
		2				400		
		3				220		
Functional test		See 4.3.1d	7	All				

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Test conditions -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit	
					Min	Max		
Propagation delay time, signal input to output	t _{PHL1} , t _{PLH1}	R _L = 200 kΩ C _L = 50 pF t _r = t _f = 20 ns See figure 4	V _{DD} = 5 V <u>3/</u>	9	01	1.5	60	ns
				10, 11		1.5	78	
			V _{DD} = 10 V <u>3/</u>	9	01	1.5	30	
				10, 11		1.5	39	
			V _{DD} = 15 V <u>3/</u>	9	01	1.5	20	
				10, 11		1.5	26	
Propagation delay time, address to signal output	t _{PHL2} , t _{PLH2}	R _L = 10 kΩ C _L = 50 pF t _r = t _f = 20 ns See figure 4	V _{DD} = 5 V <u>3/</u>	9	01	1.5	720	
				10, 11		1.5	936	
			V _{DD} = 10 V <u>3/</u>	9	01	1.5	320	
				10, 11		1.5	416	
			V _{DD} = 15 V <u>3/</u>	9	01	1.5	240	
				10, 11		1.5	312	
Propagation delay time, inhibit to signal out (channel turning ON)	t _{PZH1} , t _{PZL1}	R _L = 10 kΩ C _L = 50 pF t _r = t _f = 20 ns See figure 4	V _{DD} = 5 V	9	01	1.5	720	
				10, 11		1.5	936	
			V _{DD} = 10 V <u>1/</u>	9	01	1.5	320	
				10, 11		1.5	416	
			V _{DD} = 15 V <u>1/</u>	9	01	1.5	240	
				10, 11		1.5	312	
Propagation delay time, inhibit to signal out (channel turning OFF)	t _{PHZ1} , t _{PLZ1}	R _L = 1 kΩ C _L = 50 pF t _r = t _f = 20 ns See figure 4	V _{DD} = 5 V	9	01	1.5	450	
				10, 11		1.5	585	
			V _{DD} = 10 V <u>1/</u>	9	01	1.5	210	
				10, 11		1.5	273	
			V _{DD} = 15 V <u>1/</u>	9	01	1.5	160	
				10, 11		1.5	208	
Propagation delay time, signal input to output	t _{PHL3} , t _{PLH3}	R _L = 10 kΩ C _L = 50 pF t _r = t _f = 20 ns See figure 4	V _{DD} = 5 V	9	02		65	
				10, 11			97.5	
			V _{DD} = 10 V	9	02		30	
				10, 11			39	
			V _{DD} = 15 V	9	02		20	
				10, 11			26	
Propagation delay time, address to signal output	t _{PHL4} , t _{PLH4}	R _L = 10 kΩ C _L = 50 pF t _r = t _f = 20 ns See figure 4	V _{DD} = 5 V	9	02		720	
				10, 11			936	
			V _{DD} = 10 V	9	02		320	
				10, 11			416	
			V _{DD} = 15 V	9	02		240	
				10, 11			312	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Test conditions -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device Type	Limits		Unit	
					Min	Max		
Propagation delay time, inhibit to signal out (channel turning ON)	t _{PZH2} , t _{PZL2}	R _L = 10 kΩ C _L = 50 pF t _r = t _f = 20 ns See figure 4	V _{DD} = 5 V	9	02		720	ns
				10, 11			936	
			V _{DD} = 10 V	9	02		320	
				10, 11			420	
			V _{DD} = 15 V	9	02		240	
				10, 11			330	
Propagation delay time, inhibit to signal out (channel turning OFF)	t _{PHZ2} , t _{PLZ2}	R _L = 10 kΩ C _L = 50 pF t _r = t _f = 20 ns See figure 4	V _{DD} = 5 V	9	02		550	
				10, 11			825	
			V _{DD} = 10 V	9	02		280	
				10, 11			420	
			V _{DD} = 15 V	9	02		220	
				10, 11			330	
Propagation delay time, signal input to output	t _{PHL5} , t _{PLH5}	R _L = 1 kΩ C _L = 50 pF t _r = t _f = 20 ns See figure 4	V _{DD} = 5 V <u>4/</u>	9	03	1.5	55	
				10, 11		1.5	80	
			V _{DD} = 10 V <u>1/</u>	9	03	1.5	35	
				10, 11		1.5	50	
			V _{DD} = 15 V <u>1/</u>	9	03	1.5	25	
				10, 11		1.5	35	
Propagation delay time, address to signal output	t _{PHL6} , t _{PLH6}	R _L = 1 kΩ C _L = 50 pF t _r = t _f = 20 ns See figure 4	V _{DD} = 5 V <u>4/</u>	9	03	1.5	1000	
				10, 11		1.5	1400	
			V _{DD} = 10 V <u>1/</u>	9	03	1.5	360	
				10, 11		1.5	505	
			V _{DD} = 15 V <u>1/</u>	9	03	1.5	240	
				10, 11		1.5	335	
Propagation delay time, inhibit to signal out (channel turning ON)	t _{PZH3} , t _{PZL3}	R _L = 1 kΩ C _L = 50 pF t _r = t _f = 20 ns See figure 4	V _{DD} = 5 V <u>4/</u>	9	03	1.5	1200	
				10, 11		1.5	1800	
			V _{DD} = 10 V <u>1/</u>	9	03	1.5	450	
				10, 11		1.5	675	
			V _{DD} = 15 V <u>1/</u>	9	03	1.5	320	
				10, 11		1.5	480	
Propagation delay time, inhibit to signal out (channel turning OFF)	t _{PHZ3} , t _{PLZ3}	R _L = 1 kΩ C _L = 50 pF t _r = t _f = 20 ns See figure 4	V _{DD} = 5 V <u>4/</u>	9	03	1.5	420	
				10, 11		1.5	630	
			V _{DD} = 10 V <u>1/</u>	9	03	1.5	200	
				10, 11		1.5	300	
			V _{DD} = 15 V <u>1/</u>	9	03	1.5	150	
				10, 11		1.5	225	

1/ Guaranteed, if not tested, to the specified limits herein, only for device types 01 and 03.

2/ Subgroup 3 is performed at V_{DD} = 18 V.

3/ Guaranteed by R_{ON} test as specified in table I.

4/ Guaranteed, if not tested, for group A subgroups 10 and 11.

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Device types	01, 02, and 03
Case outlines	E and F
Terminal number	Terminal symbol
1	IN/OUT by
2	IN/OUT bx
3	IN/OUT cy
4	OUT/IN cx or cy
5	IN/OUT cx
6	INHIBIT
7	V _{EE}
8	V _{SS}
9	C
10	B
11	A
12	IN/OUT ax
13	IN/OUT ay
14	OUT/IN ax or ay
15	OUT/IN bx or by
16	V _{DD}

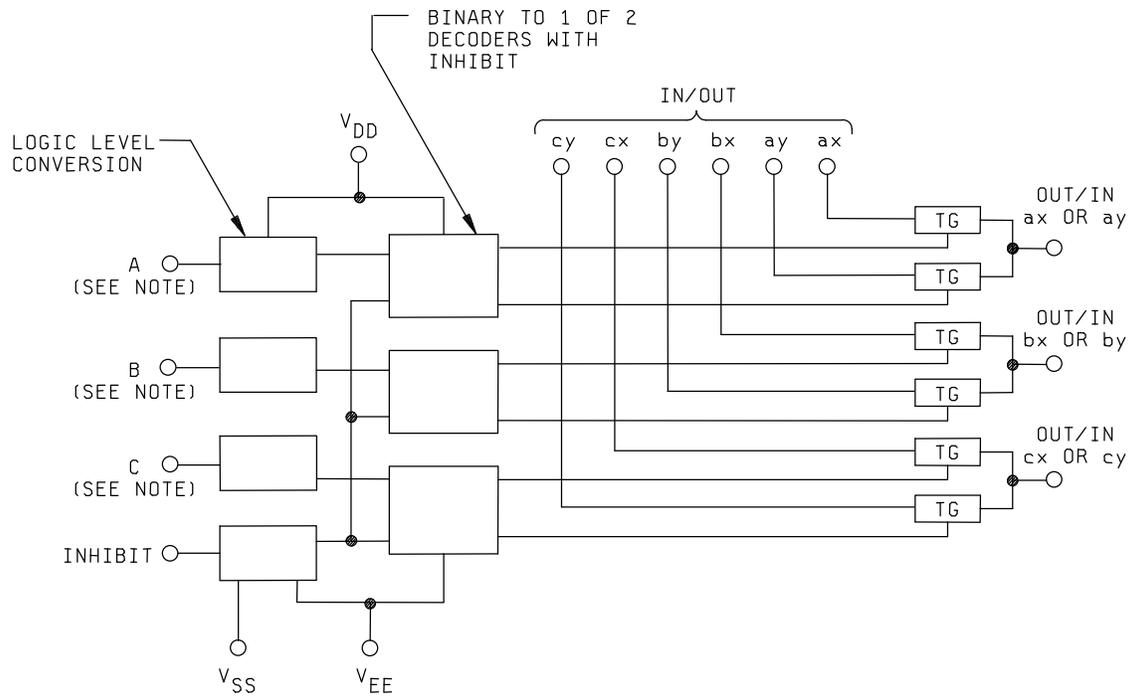
FIGURE 1. Terminal connections.

Inhibit	Select			On channels
	A	B	C	
L	L	L	L	ax, bx, cx
L	H	L	L	ay, bx, cx
L	L	H	L	ax, by, cx
L	H	H	L	ay, by, cx
L	L	L	H	ax, bx, cy
L	H	L	H	ay, bx, cy
L	L	H	H	ax, by, cy
L	H	H	H	ay, by, cy
H	X	X	X	NONE

H = High voltage level
L = Low voltage level
X = Irrelevant

FIGURE 2. Truth table.

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NOTE: All inputs protected by standard COS/MOS protection network.

FIGURE 3. Logic diagram.

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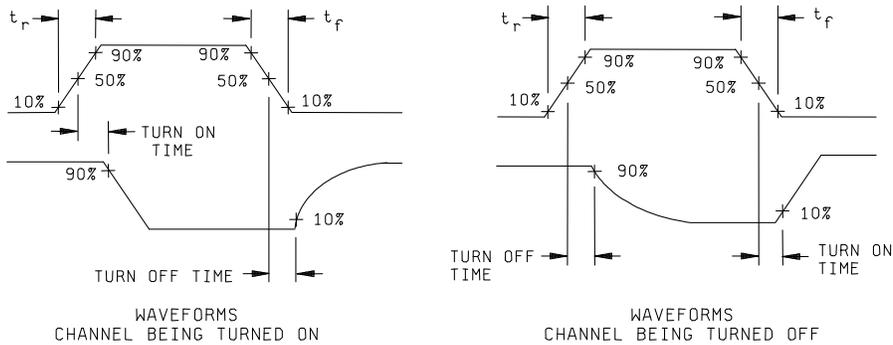
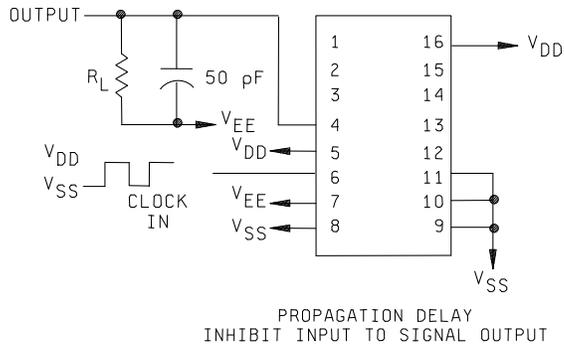
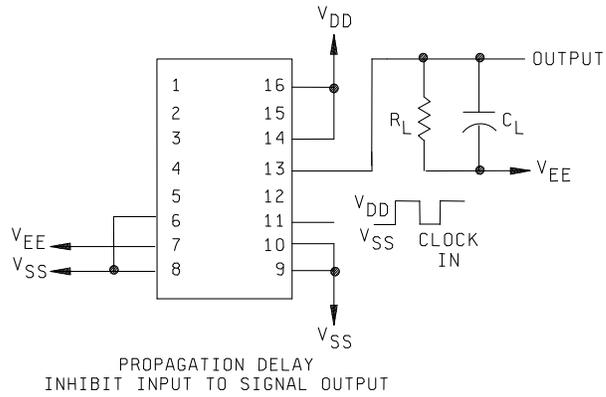


FIGURE 4. Test circuits and switching waveforms.

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4. VERIFICATION

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.

(2) $T_A = +125^\circ\text{C}$, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*, 2, 3, 7, 9
Group A test requirements (method 5005)	1, 2, 3, 4, 7, 9, 10**, 11**
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

* PDA applies to subgroup 1.

** Subgroups 10 and 11, if not tested, shall be guaranteed to the specified limits in table I.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.

c. Subgroup 4 (C_{IN} measurement) shall be measured only for the initial test and after process or design changes which may affect input capacitance. Test all applicable pins on five devices with zero failures.

d. Subgroup 7 test shall include verification of the truth table as specified in figure 2 herein.

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4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535, appendix A.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.4 Record of users. Military and industrial users shall inform DLA Land and Maritime when a system application requires configuration control and the applicable SMD to that system. DLA Land and Maritime will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DLA Land and Maritime -VA, telephone (614) 692-0544.

6.5 Comments. Comments on this drawing should be directed to DLA Land and Maritime -VA, Columbus, Ohio 43218-3990, or telephone (614) 692-0540.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DLA Land and Maritime -VA.

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DATE: 11-07-26

Approved sources of supply for SMD 81018 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DLA Land and Maritime -VA. This information bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535. DLA Land and Maritime maintains an online database of all current sources of supply at <http://www.dsccl.dla.mil/Programs/Smcr/>.

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>
8101801EA	01295	CD4053BF3A
8101801FA	<u>3/</u>	4053B
8101802EA	<u>3/</u>	14053B
8101803EA	<u>3/</u>	4053B
8101803FA	<u>3/</u>	4053B

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.
- 2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
- 3/ Not available from an approved source of supply.

Vendor CAGE number

01295

Vendor name and address

Texas Instruments Inc.
 Semiconductor Group
 8505 Forest Ln.
 P.O. Box 660199
 Dallas, TX 75243
 Point of contact: U.S. Highway 75 South
 P.O. Box 84, M/S 853
 Sherman, TX 75090-9493

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.